



Realization of Multi-Die Systems in the SysMoore Era

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A photograph of a modern, multi-story office building with a glass facade. The Synopsys logo is mounted on the upper part of the building. The building is surrounded by trees and is set against a clear blue sky. The image is partially obscured by a purple overlay on the left side.

SYNOPSYS

Outline

Market Trends

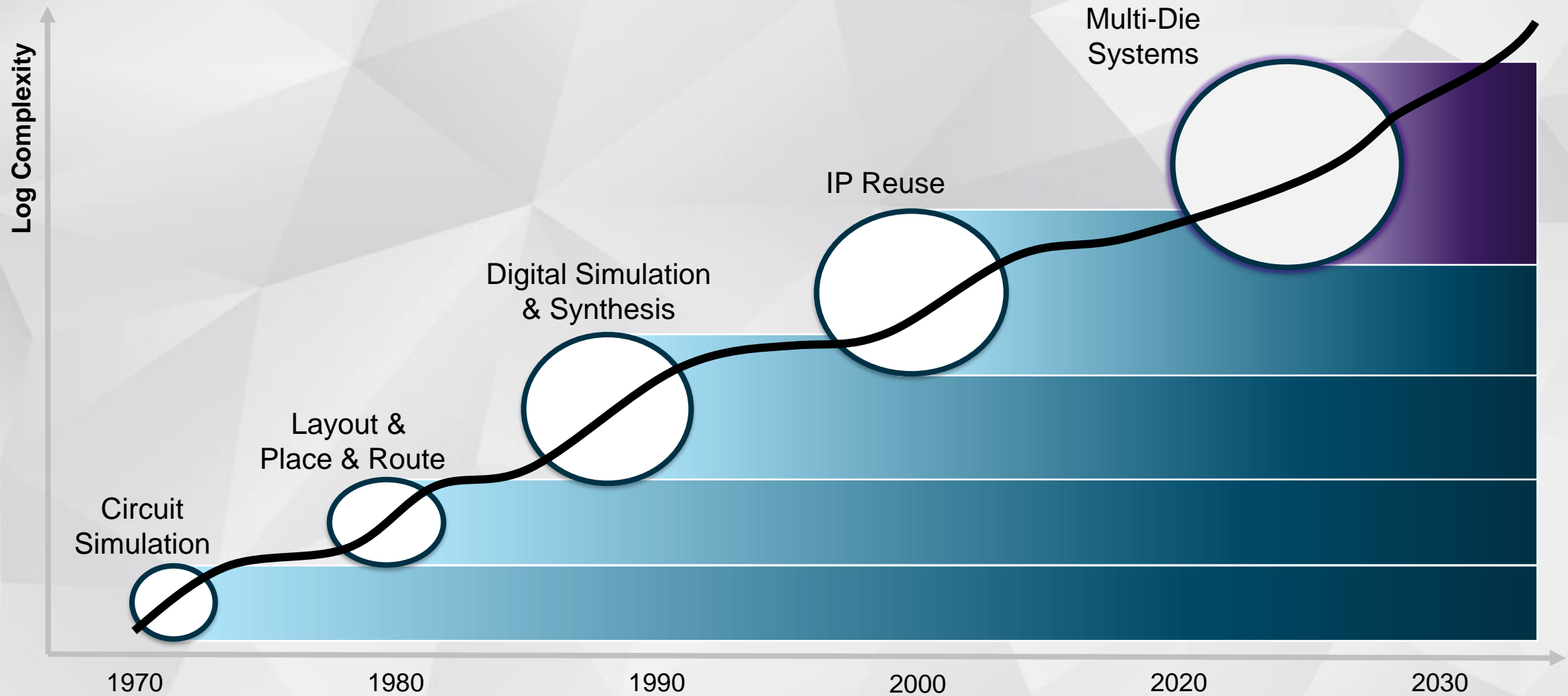
Multi-Die Design Challenges

The EDA Solution Driving Innovation

Summary

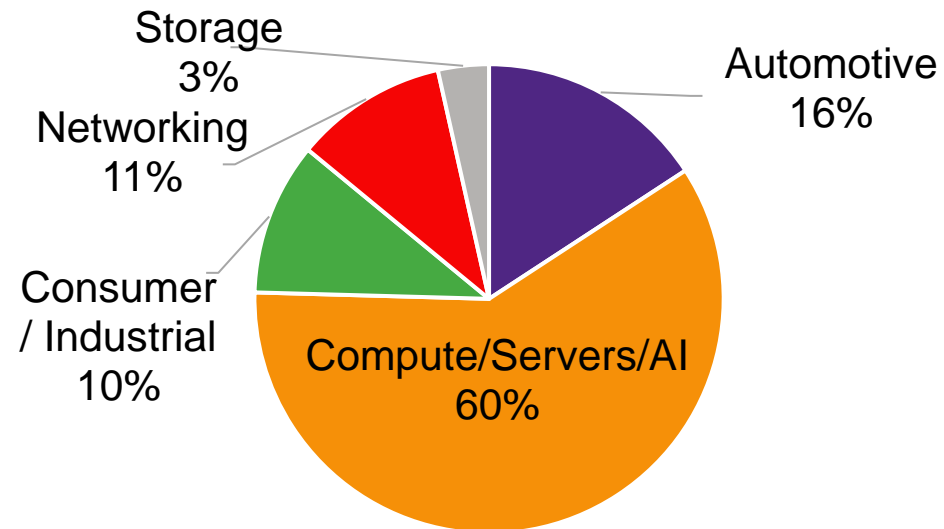
Semiconductor Design Productivity Waves

Multi-die system design: key enabler of the SysMoore era



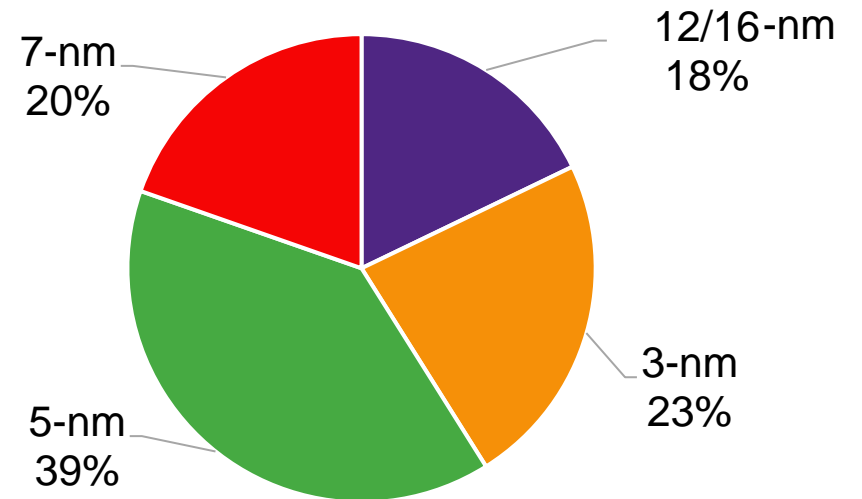
The Era of Multi-Die System Design is Already Here

Designs by Application



- The datacenter – Servers / AI – dominate
- NICs, Switches common use case
- Smartphone / Graphics / PC primarily proprietary
- Co-packaged Optics, Automotive ramping

Designs by Process Technology

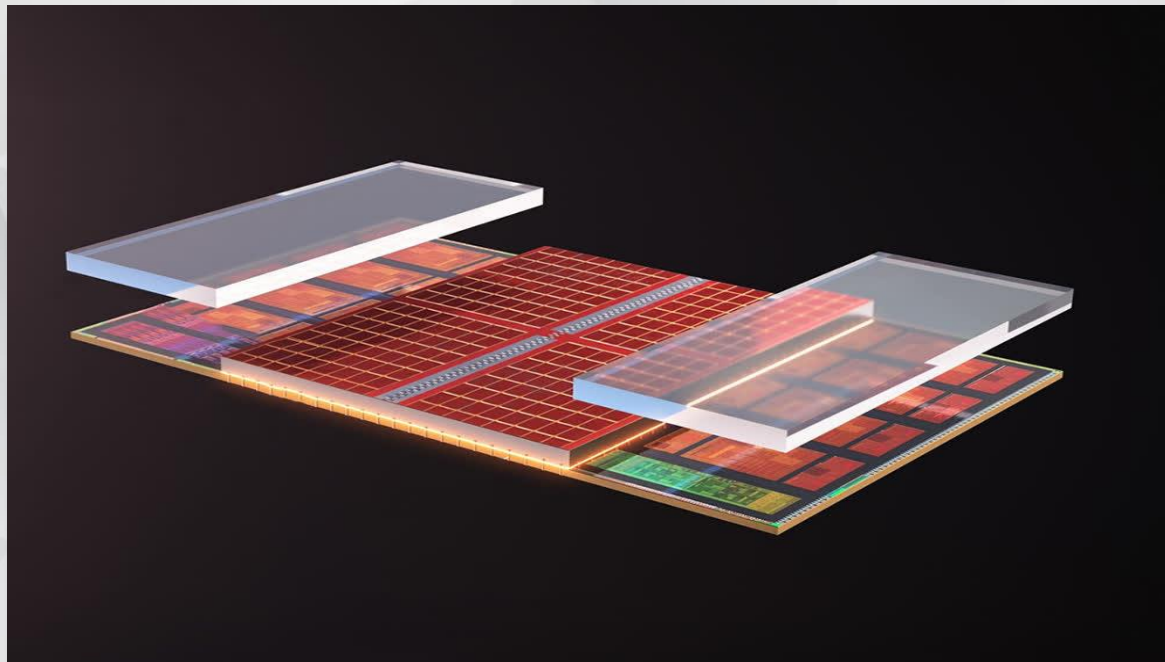


- CPU/Processors driving down Moore's law
- I/O chiplets typically in N-2, N-1 processes (e.g., 7-nm or 12-nm)

Enabling Truly Transformative Products

Examples of commercial high-performance, high-density multi-die systems

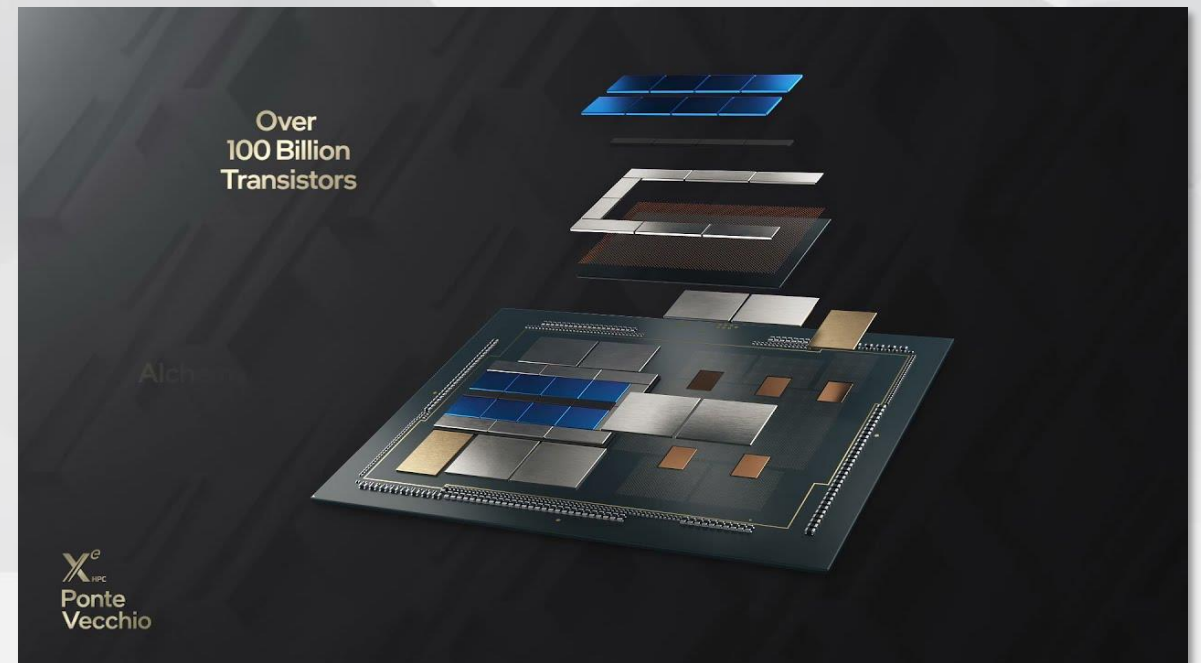
AMD



3D V-Cache: Hybrid Bonded

3x Energy Efficiency, 15x Interconnect Density
(vs. Micro-bumps)

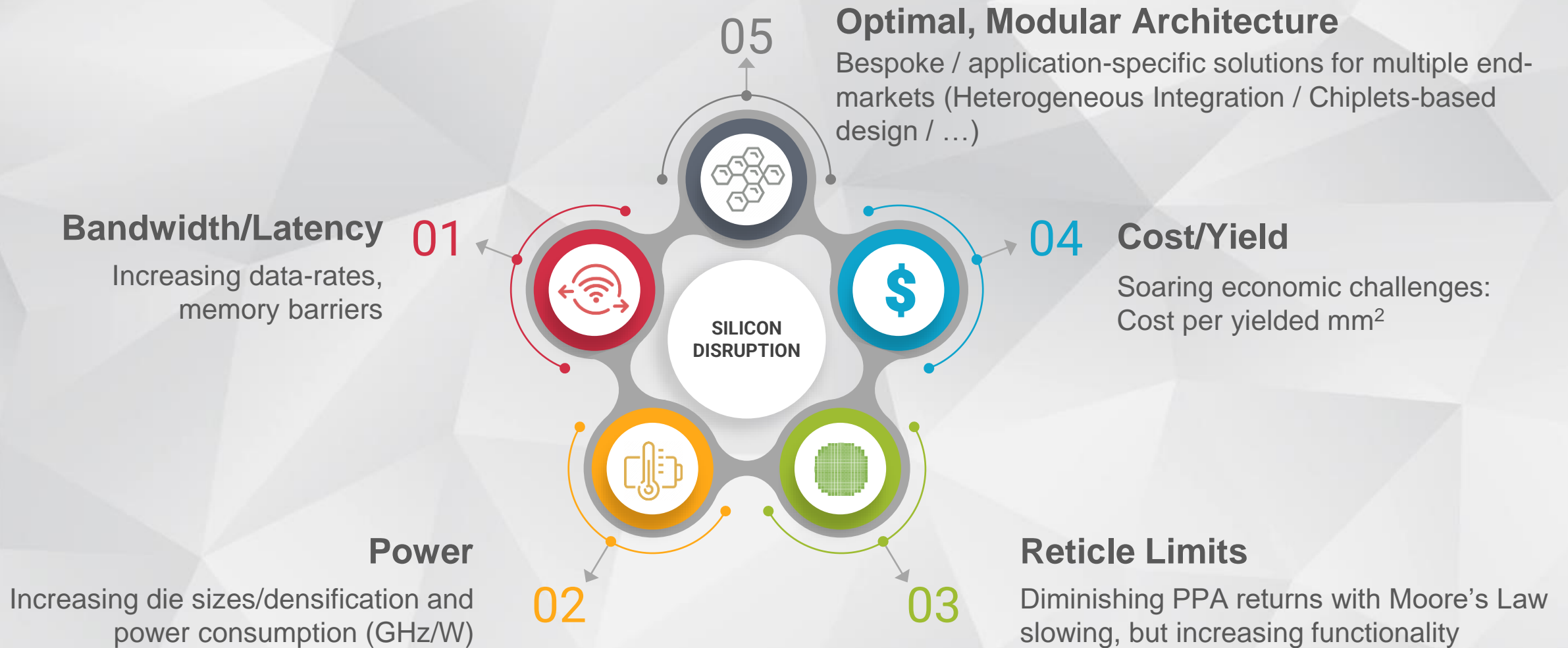
INTEL



Exascale Computing / AI

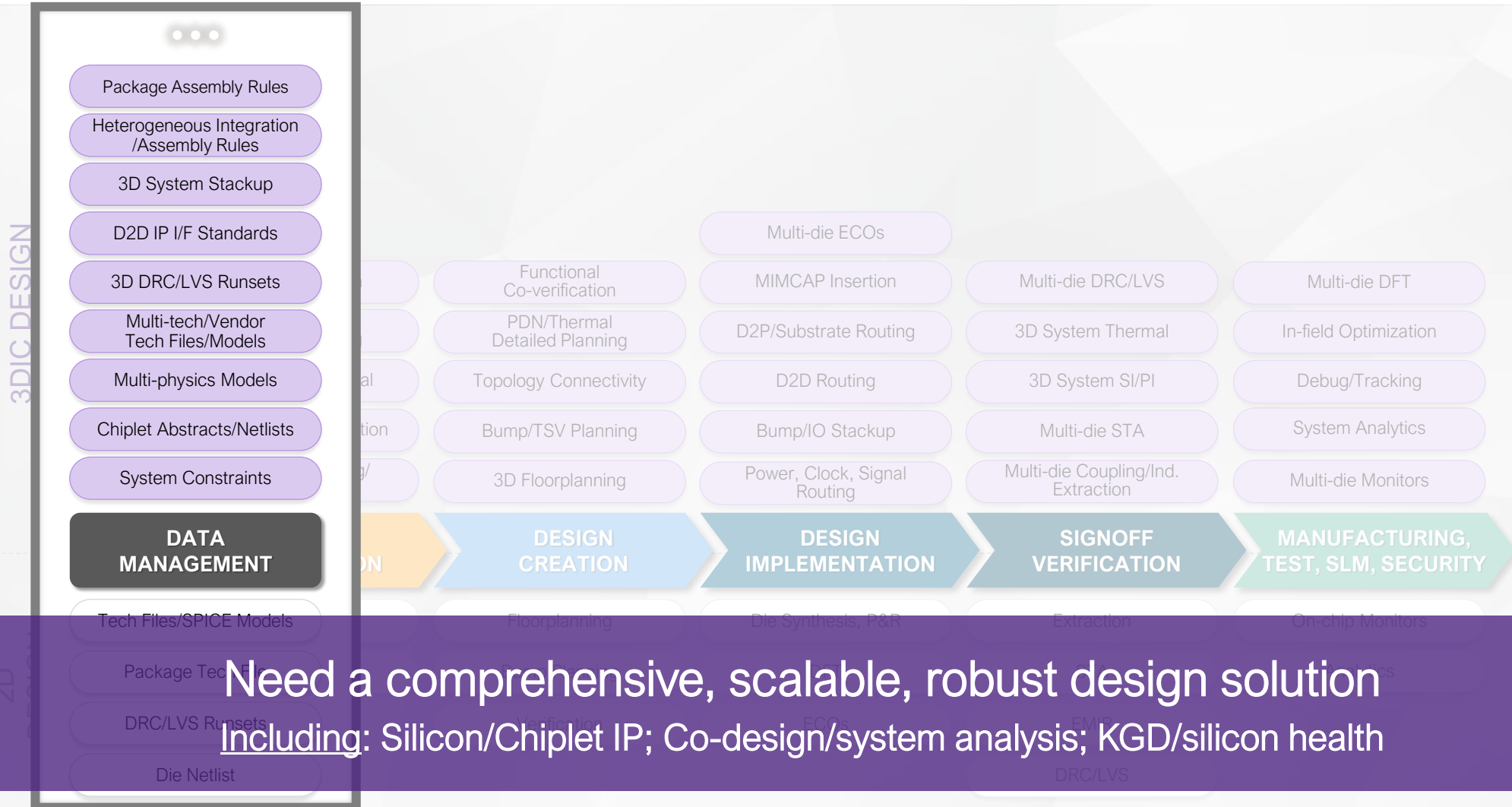
100B+ Transistors, 47 Active Tiles, 5 Process Nodes

The Drivers of Multi-Die System Design

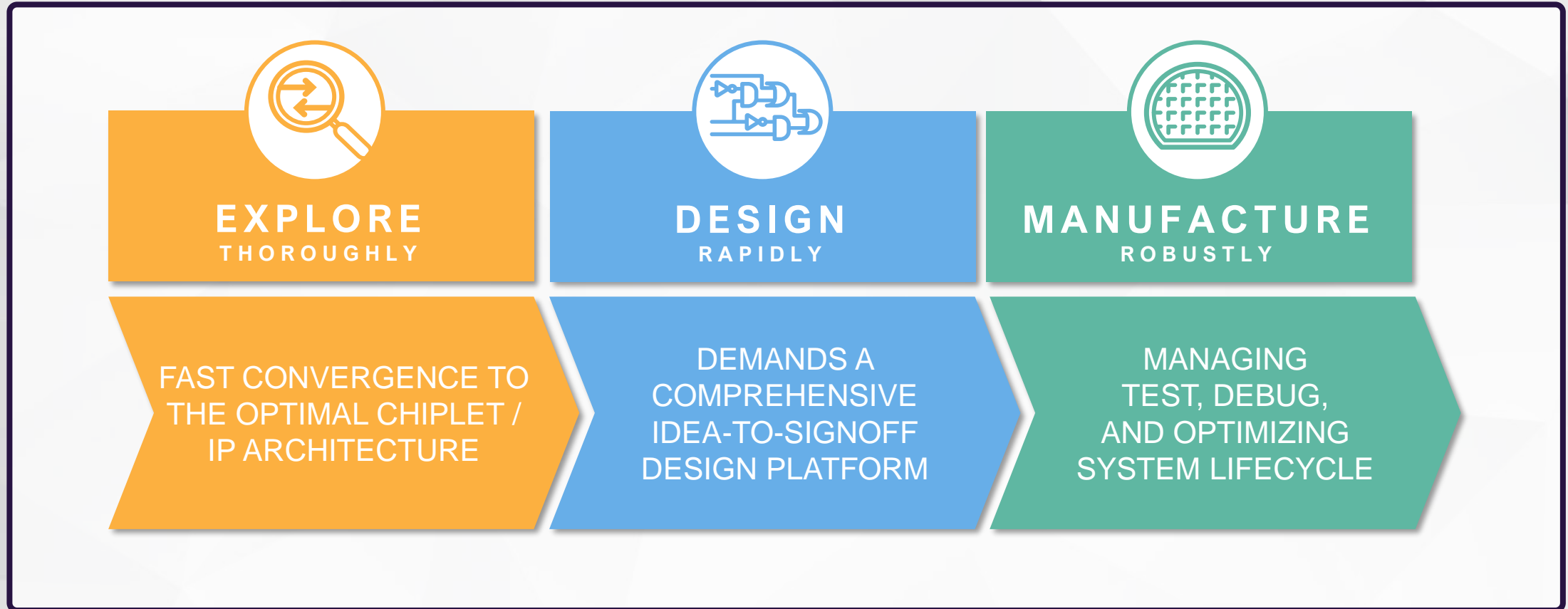


New Dimensions Bring New Opportunities... and Challenges

The multi-die/3DHI design flow is expansive – data consistency is critical



Key Facets of a Multi-Die System-Design Solution



Robust Die-to-Die Interface IP at the Heart of Multi-Die Growth

UCIe: Emerging as a preferred D2D I/F

- **Technical Merits** (Most compelling PPAs)

- Energy efficiency <0.3pJ/Bit
- Edge efficiency >5Tbps/mm
- Latency ~2ns from pin to FDI

- **Comprehensive and Futureproof**

- All use cases
- All package types
- Complete protocol stack
- Future proof with support up to 32Gbps data rate per pin

- **Broad Ecosystem**

- Wide range of promoters and contributors spanning all industry segments



Robust Die-to-Die Interface IP at the Heart of Multi-Die Growth

Synopsys' IP solutions for broad-market applications

IP PORTFOLIO

- Silicon proven
- High quality
- Secure

Foundation IP Interface IP
Security IP Processor IP

IP SUBSYSTEMS

Configured Interfaces (PCIe Subsystem)

- Pre-validated
- Integration-ready

Test Bench Environment

Controller IP Clock & Reset
Register Interface
Control Registers
Debug Module

PHY IP

IP CHIPLETS

Ethernet IO Chiplet

Ethernet

CPU (control), 112G LR PHY (N lanes), SHS Gasket, PVT Sensor, MACsec (opt), PCS, Life Cycle Mgmt Server, MAC (opt), YBAP

Memory Expander Chiplet

CPU (control), LP/DDR5 PHY (multiple), SHS Gasket, PVT Sensor, DDR Ctrl, SRAM, Life Cycle Mgmt Server, DDR Encryption, Memory Scheduler Management

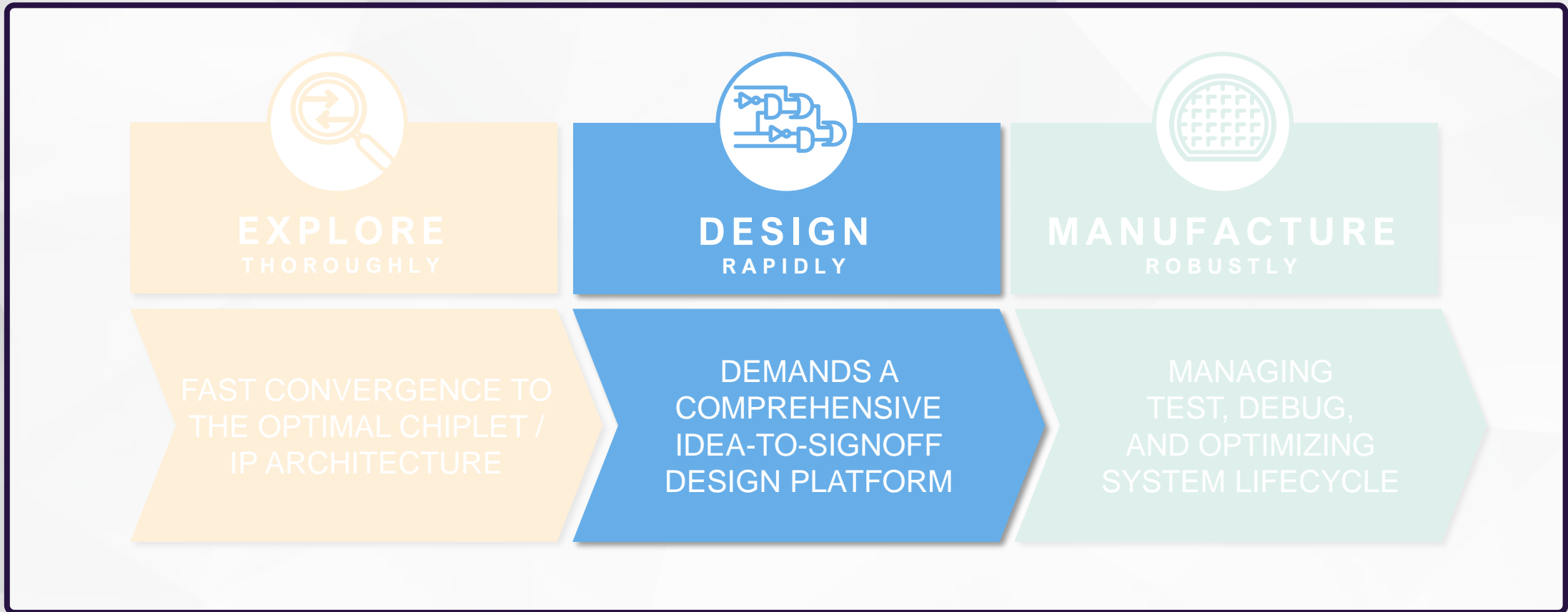
AI Accelerator Chiplet

ARC HS, SRAM Cache, SHS Gasket, PVT Sensor, Mesh network, Life Cycle Mgmt Server, ARC NPX, SHS Sensor (DFT), JTAG (Test Sensors), Root of Trust, Security Extension, D2D Ctrl, D2D PHY (UCle/XSR), SHS Gasket, PVT Sensor, D2D Interface, Reference Clocks

SYNOPSYS IP CHIPLETS

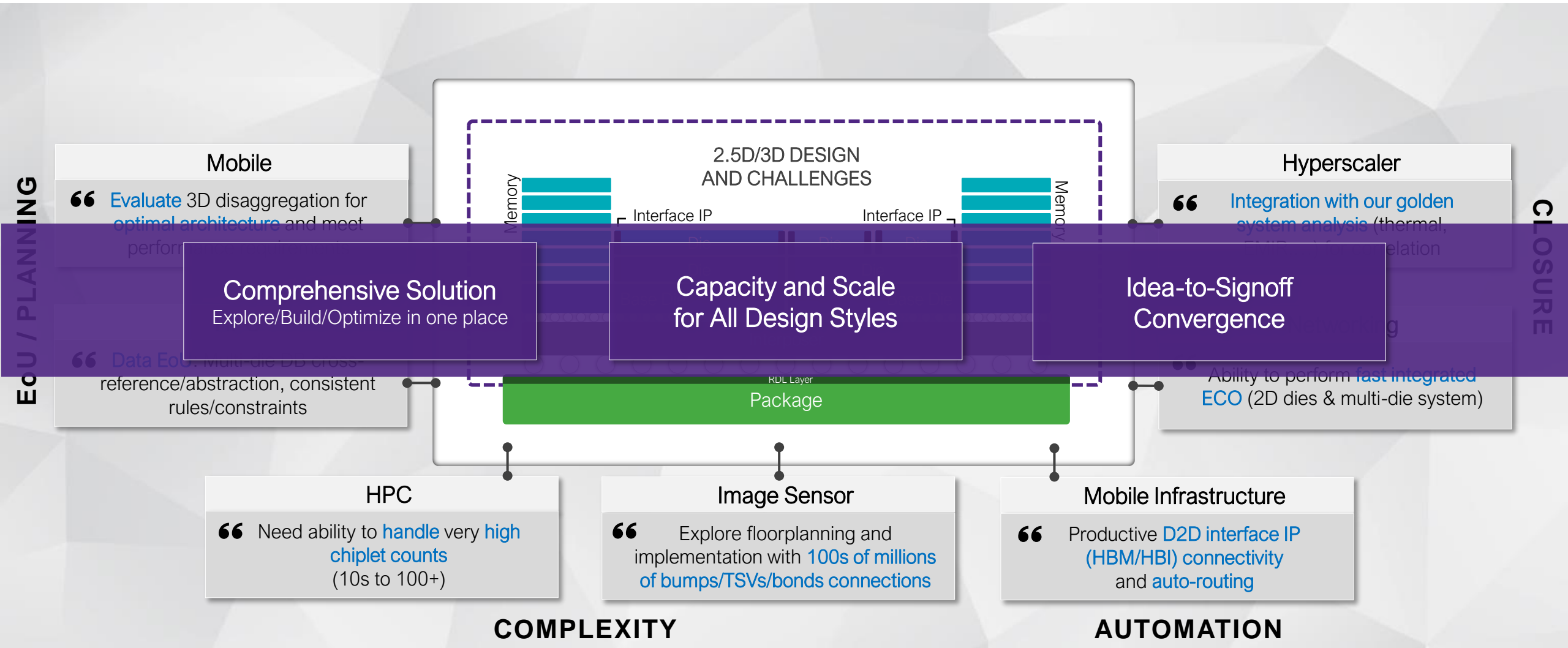
- Built on Synopsys' silicon-proven, high-quality IP portfolio
- Flexibility to support multiple package types
- Customizable to target application
- Key features
 - Standards-compliant interfaces
 - Hierarchical test
 - Built-in security
 - SLM support
 - Yield enhancement functionality

Key Facets of a Multi-Die System-Design Solution



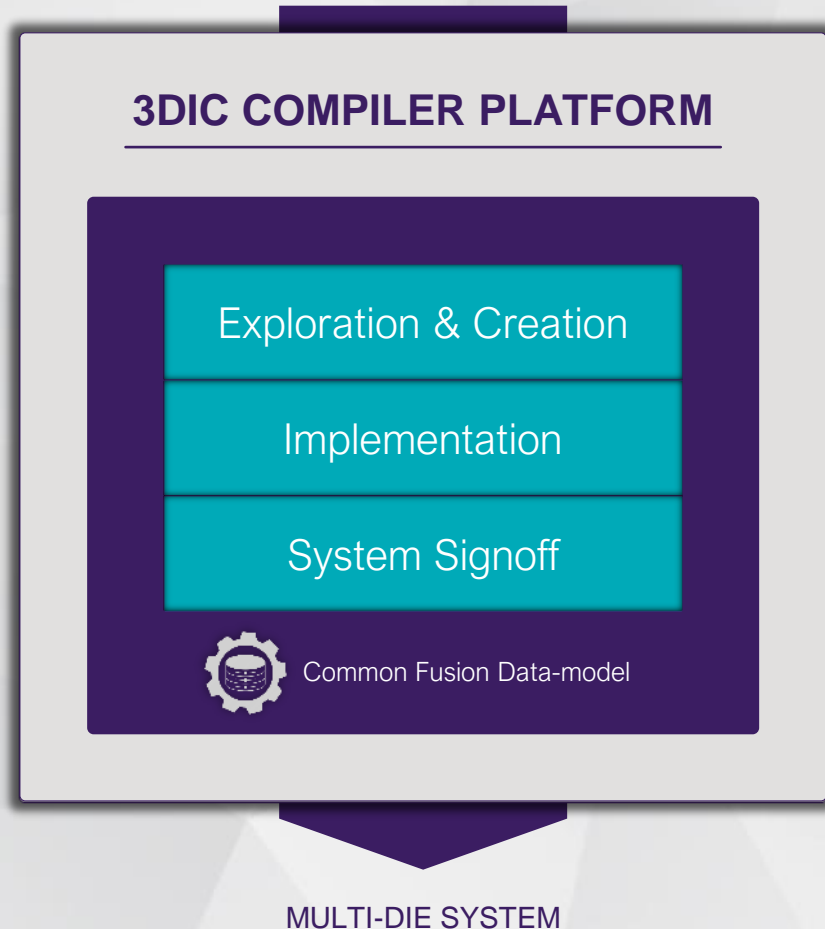
Multi-Die Design Requires a Re-Evaluation of Needs

A broader scope of challenges and demands



The Synopsys Unified Platform for Multi-Die System Design

Full-scope system-level co-design and analysis



A Highly Scalable Platform

Heterogeneous integration of 100s of billions of transistors
Billion+ inter-connections in a few hours



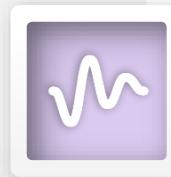
Seamless 2D to 3D Design Continuity

Common data-model and tech-files
Efficient, concurrent workflow for faster closure



Unified Full-Flow Productivity

Single environment for full system design
Full breadth engines: design, test, analysis, verification

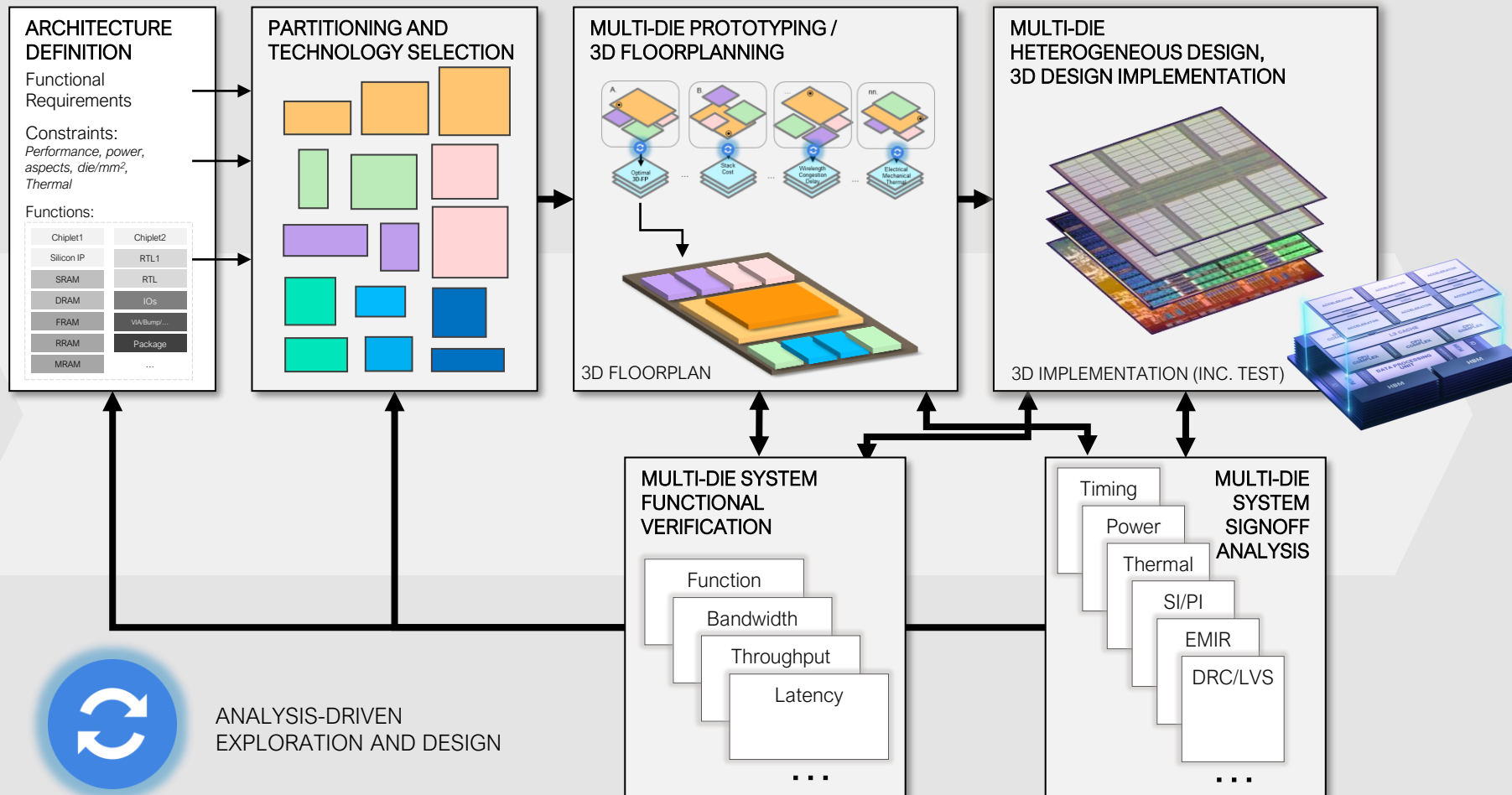


Trusted, Golden-Signoff Analysis

Industry-leading technologies – STA, Thermal, EMIR, SI/PI
Fast convergence to optimal PPA/mm³, accelerate tapeout

Convergence and Closure Demands Analysis-Driven Design

Create, Implement, Refine, Converge – A 3DHI example

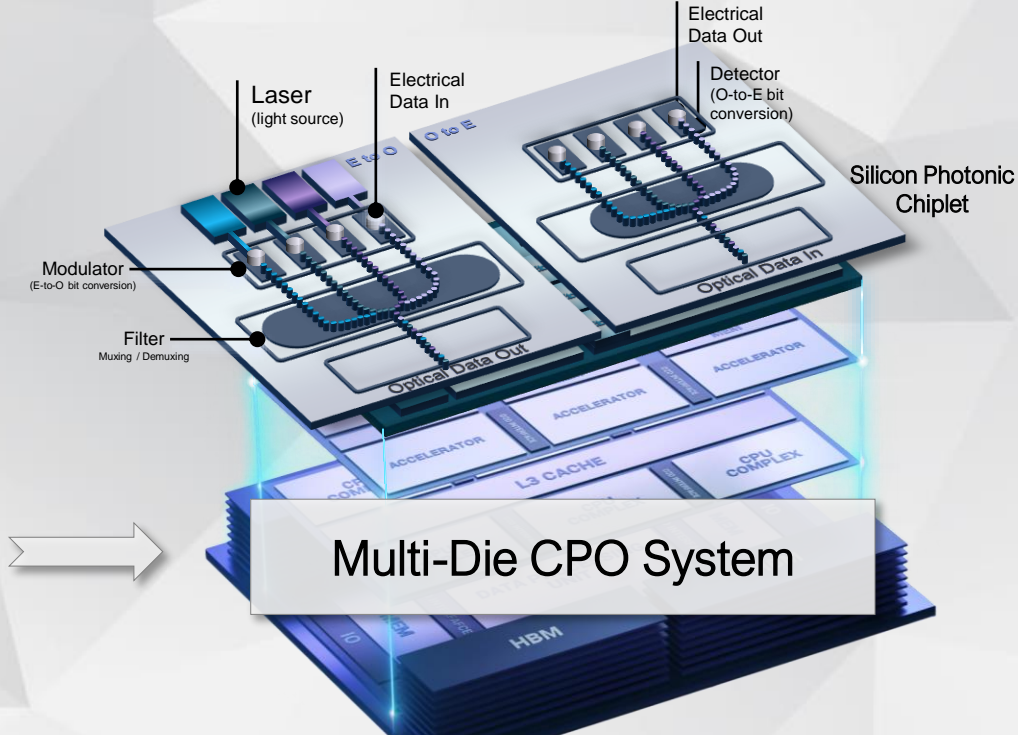
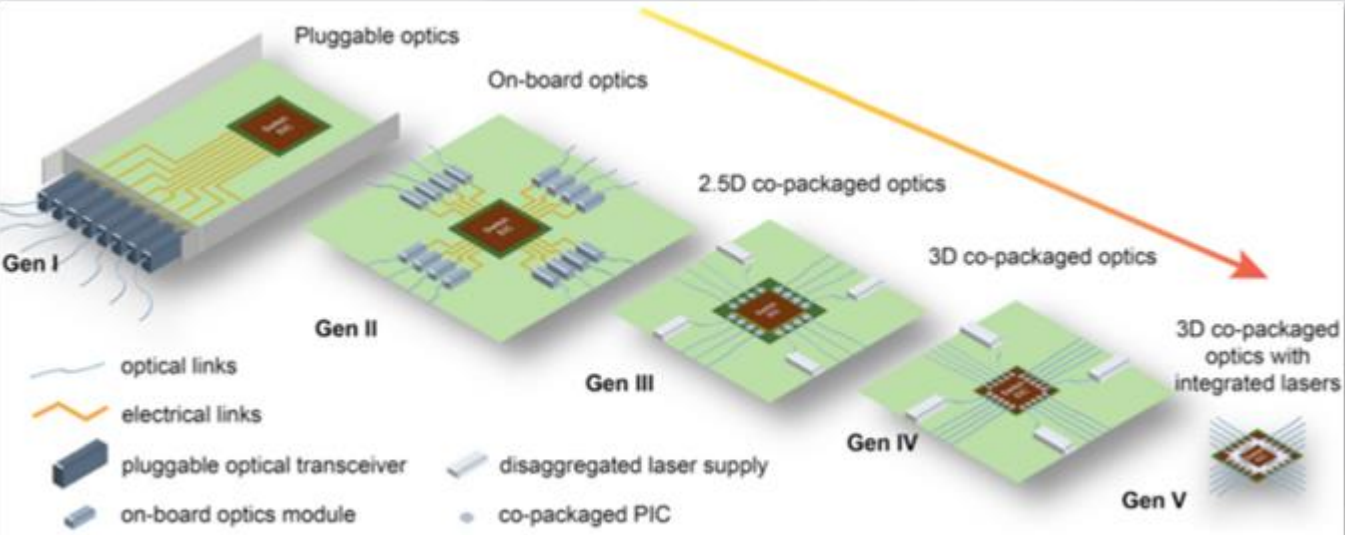


- Full, partial, or zero netlist design entry for multi-die feasibility analysis
- Auto extraction / abstraction of IP and connectivity from existing 2D dies/modules
- Multi-fab/-node IP and block management support
- Fast floor-planning and connectivity optimization using 3D analytical assessment

The Co-Packaged Optics (CPO) Solution to Performance

The silicon-photonic chiplet – Another die in a multi-die system

Generational progression:
Tighter integration between Datacenter Switches and Optical IO



Source: John Bowers, UCSB

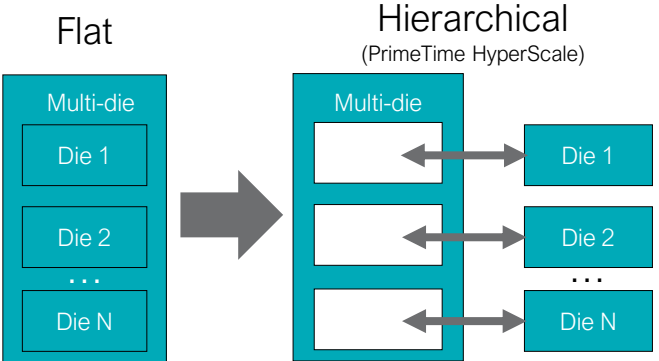
3DIC COMPILER
Multi-Die Heterogeneous-Integration Platform



OPTO COMPILER
Photonic Chiplet Design

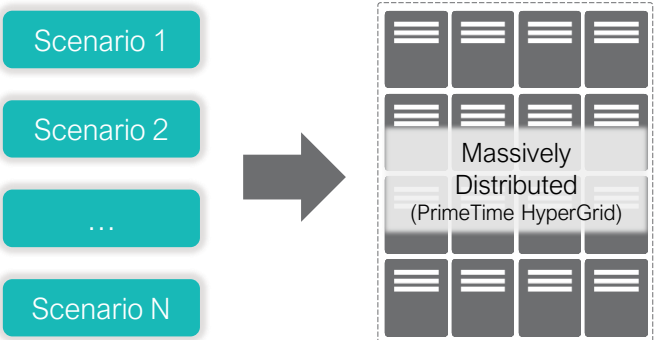
Achieving Golden Signoff for Multi-Die Systems

STATIC TIMING ANALYSIS AT SCALE



Hierarchical Signoff

Runtime and memory efficiency with full flat accuracy

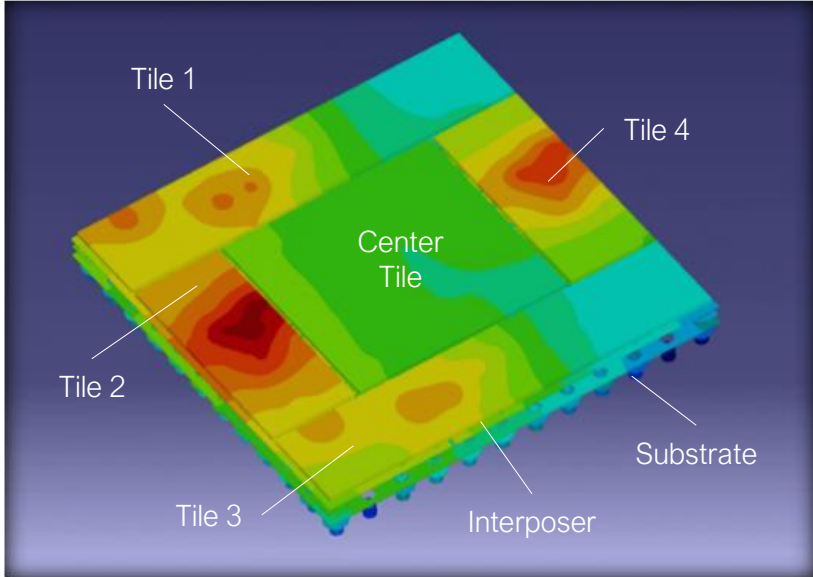


Resource Maximization

Multi-scenario/corner, cloud native + Smart corner reduction (10x)

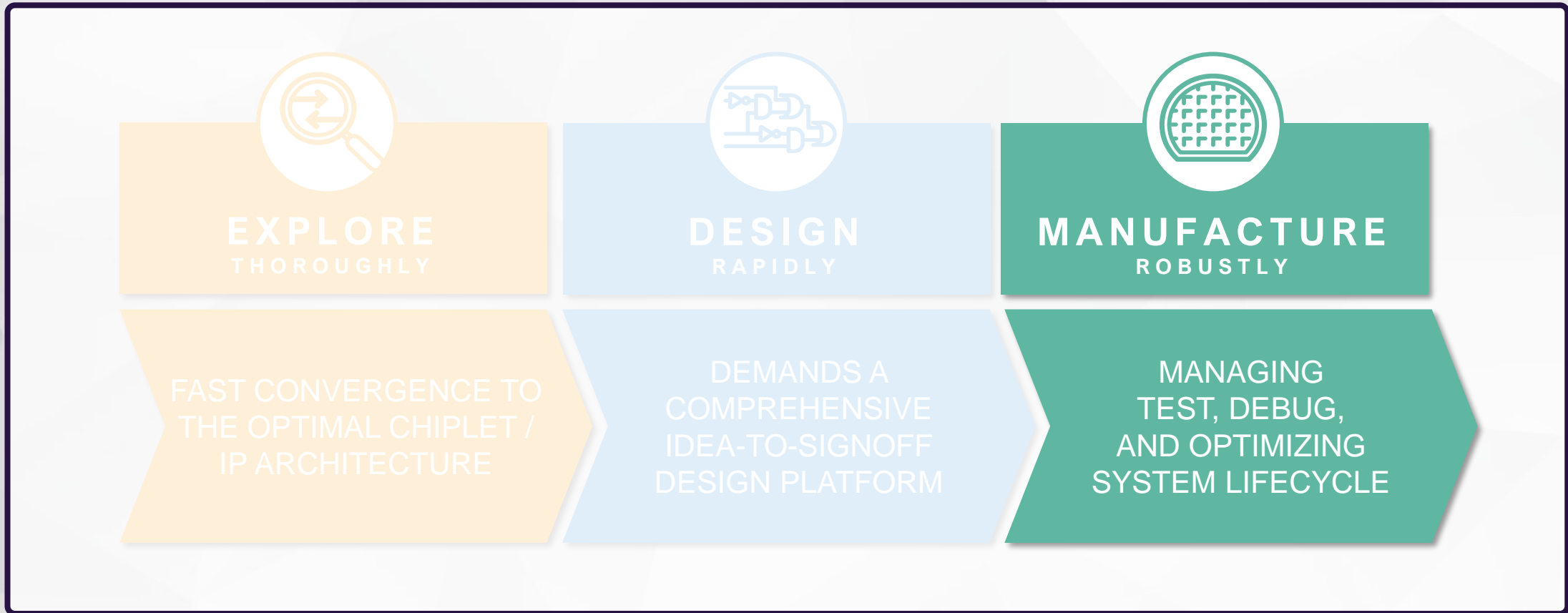
THERMAL ANALYSIS AT SCALE

Integrated System-level Hierarchical Thermal Analysis



Courtesy: Ansys

Key Facets of a Multi-Die System-Design Solution

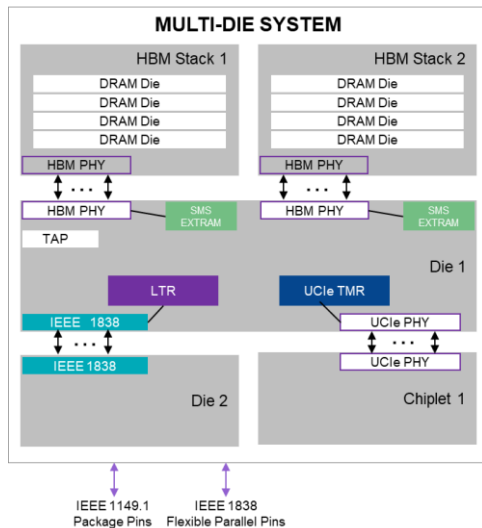


Enabling the Manufacturing Ramp and Product Reliability

Synopsys' TestMAX and the SLM Family of products

MULTI-DIE SYSTEM TEST AND REPAIR

PRODUCT QUALITY (KGD, Package, System)



Ensure quality with comprehensive test, debug, repair for multi-die systems

Integrated Test for: Multiple Dies, Memories, Interconnects, and Full-system

Test Access
IEEE 1838

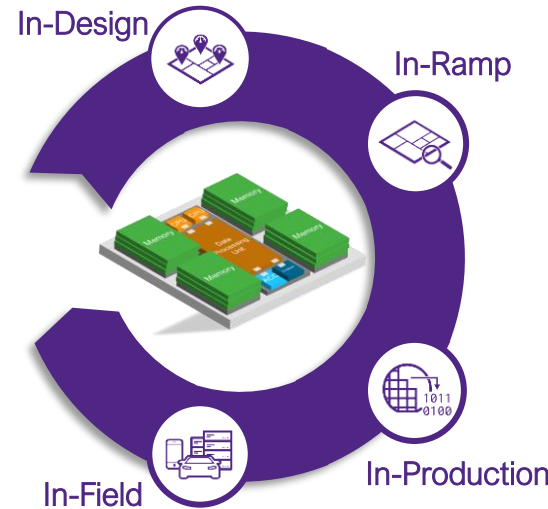
Logic-to-Logic
PHY Monitor, Test & Repair

Logic-to-Memory
Ext. Memory BIST & Repair

Via / Bump / Interconnect
High volume Lane Test & Repair

SILICON LIFECYCLE MANAGEMENT

RELIABILITY, YIELD, HEALTH



Enhance multi-die system operational metrics through environmental, structural, functional monitoring

Solution comprises: Silicon IP, EDA Software, and Analytics Insights

In-Design
Power/Performance Optimization

In-Ramp
Yield, Failure Diagnosis

In-Production
Volume Test, Quality and Traceability

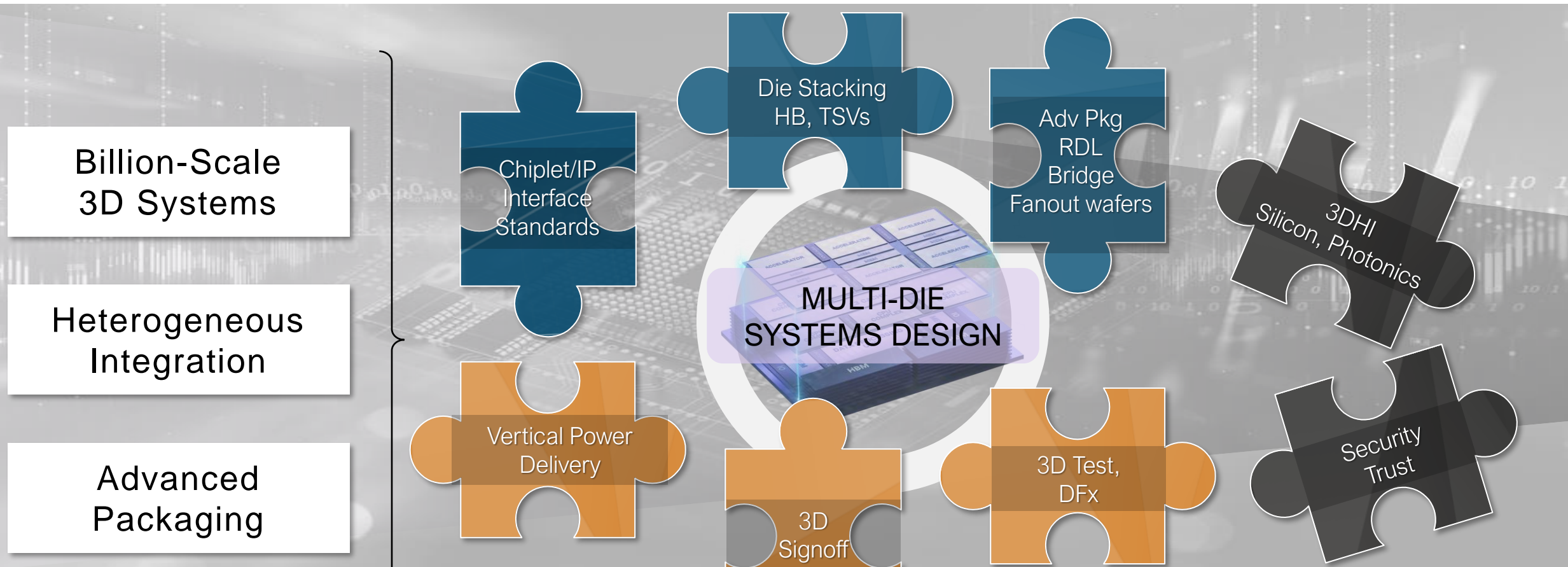
In-Field
Optimization, Safety, Security, Maintenance

Summary



Multi-Die Systems: The Next Wave in Semiconductor Design

New Dimensions, *New Challenges*, New Opportunities...



Need a holistic solution for efficient multi-die system design, and industry-wide collaborations to catalyze *SysMoore Era* innovations

SYNOPSYS[®]
Silicon to Software™

THANK YOU